Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/003,557	CHANG ET AL.	
Examiner	Art Unit	_
Nhon T. Diep	2621	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Fast Search	10/13/06	M.D.	
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